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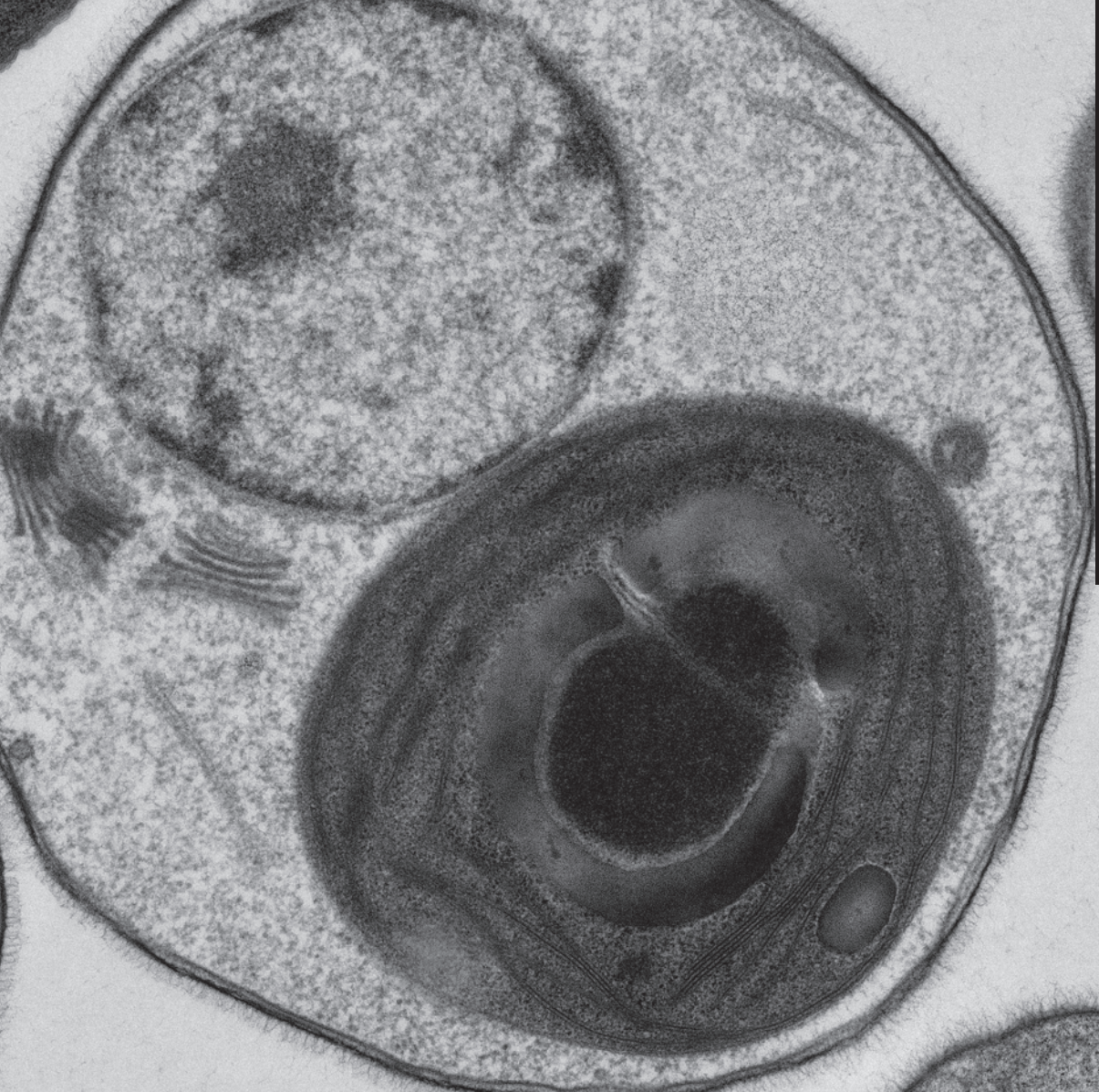
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Microscopy AND Microanalysis



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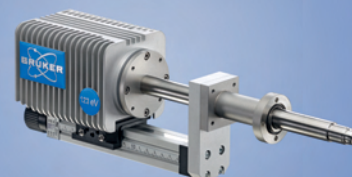
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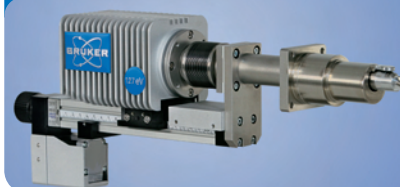
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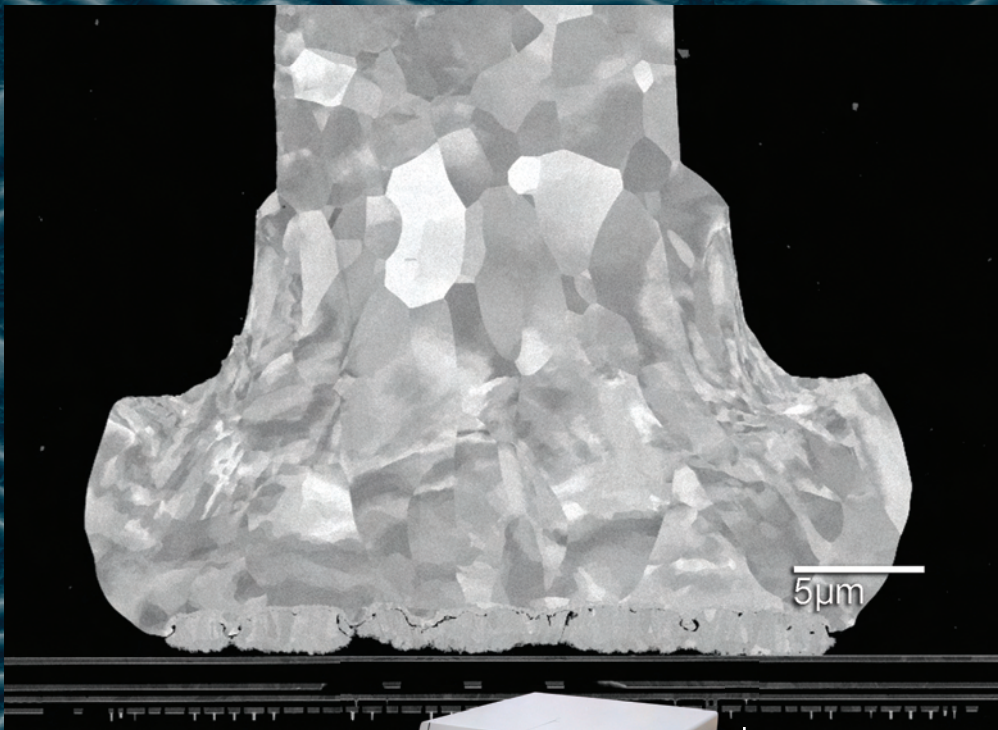


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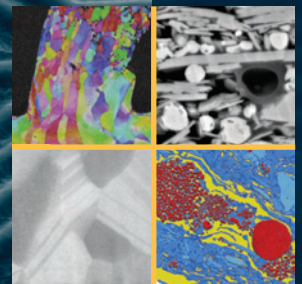
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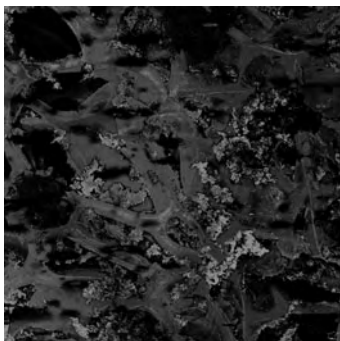
October 2010

BIOLOGICAL APPLICATIONS

- Synchrotron UV Fluorescence Microscopy Uncovers New Probes in Cells and Tissues 507
Frederic Jamme, Sandrine Villette, Alexandre Giuliani, Valerie Rouam, Frank Wien, Bruno Lagarde, and Matthieu Réfrégiers
- On the Suitability of SIFT Technique to Deal with Image Modifications Specific to Confocal Scanning Laser Microscopy 515
Stefan G. Stanciu, Radu Hristu, Radu Boriga, and George A. Stanciu
- Characterization of Healthy and Fluorotic Enamel by Atomic Force Microscopy 531
Verónica Zavala-Alonso, Gabriel A. Martínez-Castanon, Nuria Patiño-Marín, Humberto Terrones, Kenneth Anusavice, and Juan P. Loyola-Rodríguez
- Scanning Electron and Confocal Scanning Laser Microscopy Imaging of the Ultrastructure and Viability of Vaginal *Candida albicans* and Non-*Albicans* Species Adhered to an Intrauterine Contraceptive Device 537
Luciene C. Farias Paiva, Lucélia Donatti, Eliana V. Patussi, Terezinha I.E. Svizdinski, and Márcia E. Lopes-Consolaro
- Spatial Architecture of Nitrifying Bacteria Biofilm Immobilized on Polyurethane Foam in an Automatic Biodetector for Water Toxicity 550
Andrzej Woznica, Jagna Karcz, Agnieszka Nowak, Aleksander Gmur, and Tytus Bernas
- Dilution and Magnification Effects on Image Analysis Applications in Activated Sludge Characterization 561
D.P. Mesquita, O. Dias, R.A.V. Elias, A.L. Amaral, and E.C. Ferreira
- Suberized Cell Walls of Cork from Cork Oak Differ from Other Species 569
Rita Teresa Teixeira and Helena Pereira
- Influence of Blue Light on the Leaf Morphoanatomy of *In Vitro Kalanchoe pinnata* (Lamarck) Persoon (Crassulaceae) 576
Marcos Vinicius Leal-Costa, Luana Beatriz dos Santos Nascimento, Nattacha dos Santos Moreira, Fernanda Reinert, Sônia Soares Costa, Celso Luiz Salgueiro Lage, and Eliana Schwartz Tavares

MICROANALYSIS APPLICATIONS

- Effects of the Carbon Coating and the Surface Oxide Layer in Electron Probe Microanalysis 583
Silvina P. Limandri, Alejo C. Carreras, and Jorge C. Trincavelli
- X-Ray Mapping and Scatter Diagram Analysis of the Discoloring Products Resulting from the Interaction of Artist's Pigments 594
Rachel White, Paul Thomas, Matthew R. Phillips, Ken Moran, and Richard Wuhrer



On the Cover: Confocal image of nitrifying bacteria biofilm used in an automatic biodetector for water toxicity. For further information see Woznica et al. on page 550.

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STEM DEVELOPMENT AND APPLICATIONS

Diffraction Imaging in a He⁺ Ion Beam Scanning Transmission Microscope 599
John Notte IV, Raymond Hill, Sean M. McVey, Ranjan Ramachandra, Brendan Griffin, and David Joy

Quantification of Sample Thickness and In-Concentration of InGaAs Quantum Wells by Transmission Measurements in a Scanning Electron Microscope 604
T. Volkenandt, E. Müller, D.Z. Hu, D.M. Schaadt, and D. Gerthsen

D-STEM: A Parallel Electron Diffraction Technique Applied to Nanomaterials 614
K.J. Ganesh, M. Kawasaki, J.P. Zhou, and P.J. Ferreira

Microfluidic System for Transmission Electron Microscopy 622
Elisabeth A. Ring and Niels de Jonge

ATOMIC FORCE AND ATOM PROBE APPLICATIONS

An Operating Method with Lateral Scan for Reducing the Error in Topography Caused by the Tip-Sample Angle in Atomic Force Microscopy 630
Fa-Quan Zhou, Xue-Zeng Zhao, Fei Wang, and Yue-Yu Wang

Atom Scale Characterization of the Near Apex Region of an Atomic Force Microscope Tip 636
Christopher J. Tourek and Sriram Sundararajan

Clustering and Local Magnification Effects in Atom Probe Tomography: A Statistical Approach 643
Thomas Philippe, Maria Gruber, François Vurpillot, and D. Blavette

BOOK REVIEW

Live Cell Imaging, A Laboratory Manual, 2nd edition. Robert D. Goldman, Jason R. Swedlow, and David L. Spector (Eds.). 649
Zehra F. Nizami

CALENDAR OF MEETINGS AND COURSES 650

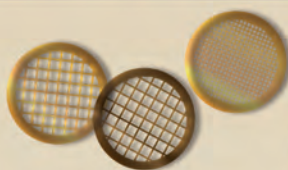


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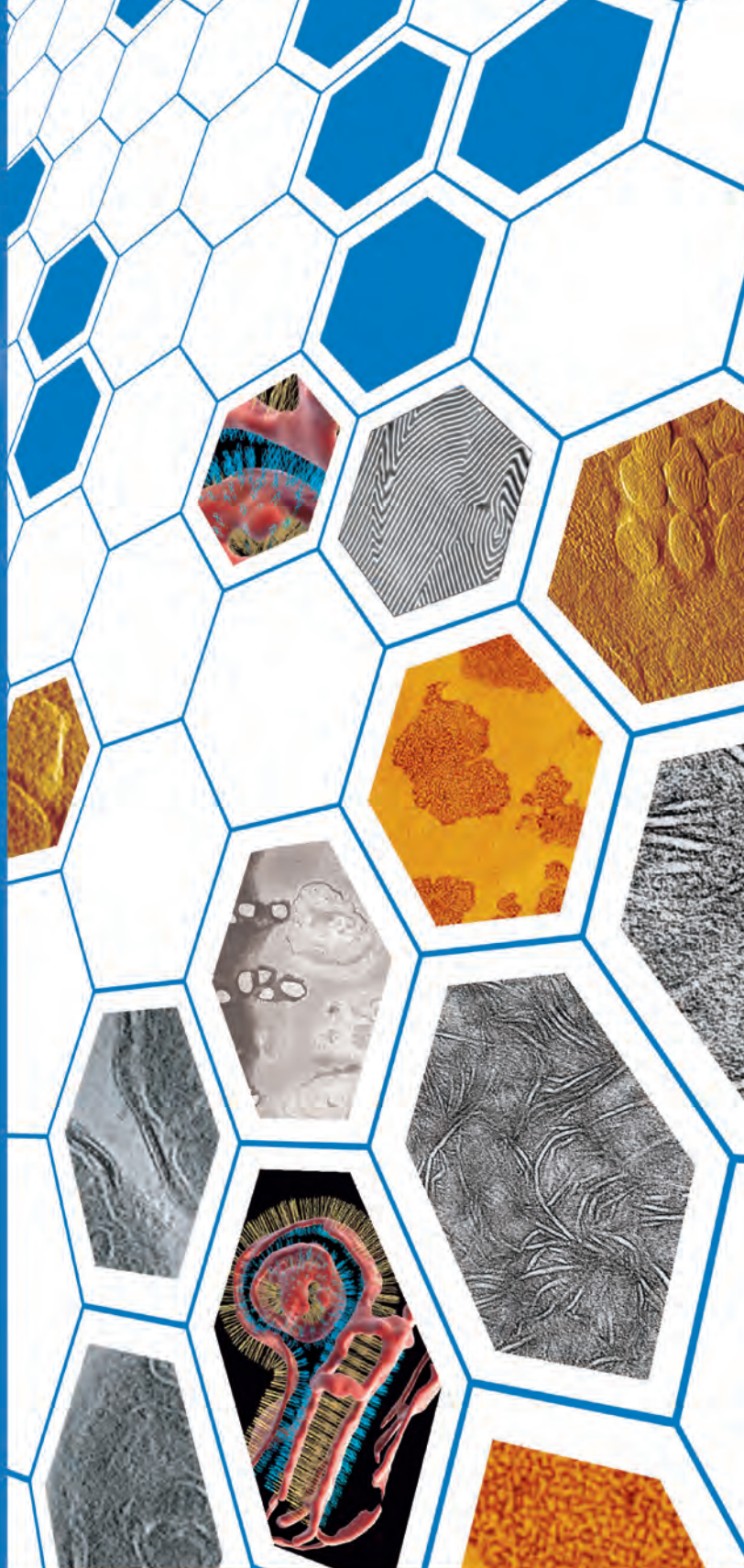
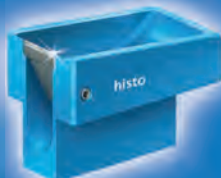
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